EAST Search History

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L1	20	high near3 resolution with two adj4 (phase) near5 two	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/17 08:36
L2	216	high near3 resolution with two adj4 (phase)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/17 08:48
L3	27	high near3 resolution with two adj4 (phase) and (ccd or cmos)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/17 08:56
L4	71	high near3 resolution with two adj4 (phase) and (ccd or cmos or sensor)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/17 09:06
L5	464	257/246-248.ccls.	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/17 09:06
L6	0	257/246-248.ccls. and highn near4 resolution	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/17 09:07
L7	31	257/246-248.ccls. and high near4 resolution	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/17 09:07

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L10	46	(chang$4 or select$4) with mode with high with low with resolution and shift adj register	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/17 11:43
L11	37	(chang$4 or select$4) with mode with high with low with resolution and shift adj register and (clock or phase)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/17 11:44
L12	28	(chang$4 or select$4) with mode with high with low with resolution and shift adj register and (clock or phase)and gate	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/17 11:50
L13	53	high with low with resolution with phase and shift adj register	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/17 11:51

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<u>Electron Devices, IEEE Transactions on</u>
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